

SiHFPF40-VB Datasheet

N-Channel 900V (D-S) Super Junction Power MOSFET

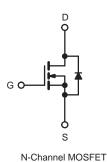
PRODUCT SUMMARY					
V _{DS} (V)	900				
R _{DS(on)} (Ω)	V _{GS} = 10 V 1.3				
Q _g (Max.) (nC)	200				
Q _{gs} (nC)	24				
Q _{gd} (nC)	110				
Configuration	Single				

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC



Top View



PARAMETER	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	V _{DS}	900	V	
Gate-Source Voltage	V _{GS}	± 20		
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 \degree C$	Ι _D	5	
	$T_{\rm C} = 100 ^{\circ}{\rm C}$		3.9	A
Pulsed Drain Current ^a	I _{DM}	21		
Linear Derating Factor		1.5	W/°C	
Single Pulse Avalanche Energy ^b	E _{AS}	770	mJ	
Repetitive Avalanche Current ^a	I _{AR}	7.8	A	
Repetitive Avalanche Energy ^a	E _{AR}	19	mJ	
Maximum Power Dissipation	T _C = 25 °C	PD	190	W
Peak Diode Recovery dV/dt ^c	dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	
Mounting Torque	6-32 or M3 screw		10	lbf ∙ in
Mounting Torque	0-32 OF IVI3 SCIEW	F	1.1	N · m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 23 mH, $R_g = 25 \Omega$, $I_{AS} = 7.8 \text{ A}$ (see fig. 12). c. $I_{SD} \le 7.8 \text{ A}$, dl/dt $\le 140 \text{ A/}\mu\text{s}$, $V_{DD} \le 600 \text{ V}$, $T_J \le 150 \text{ °C}$. d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply



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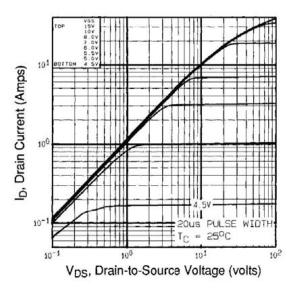
THERMAL RESISTANCE RATI	NGS							
PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum Junction-to-Ambient	R _{thJA}	- 40 0.24 - - 0.65						
Case-to-Sink, Flat, Greased Surface	R _{thCS}				°C/W			
Maximum Junction-to-Case (Drain)	R _{thJC}							
		. N						
SPECIFICATIONS ($T_J = 25 \text{ °C}, u$		1			[
PARAMETER	SYMBOL	TES	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		1				1	1	1
Drain-Source Breakdown Voltage	V _{DS}		= 0 V, I _D =	-	900	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$		e to 25 °C,		-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V_{GS} , I_D =	250 µA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20$	V	-	-	± 100	nA
Zero Gate Voltage Drain Current	1000	V _{DS} =	$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}$		-	-	100	
	I _{DSS}			/, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	١ _c	₀ = 3.7 A ^b	-	1.3	-	Ω
Forward Transconductance	g fs	V _{DS} =	100 V, I _D =	= 3.7 A ^b	5.6	-	-	S
Dynamic								
Input Capacitance	C _{iss}		V _{GS} = 0 V	,	-	3100	-	
Output Capacitance	C _{oss}]	$V_{DS} = 25 V,$		-	800	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, se	e fig. 5	-	490	-	1
Total Gate Charge	Qg				-	-	200	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		A, V _{DS} = 400 V, ig. 6 and 13 ^b	-	-	24	
Gate-Drain Charge	Q _{gd}		5001		-	-	110	
Turn-On Delay Time	t _{d(on)}				-	19	-	1
Rise Time	tr		V _{DD} = 400 V, I _D = 3.8 A,		-	38	-	1
Turn-Off Delay Time	t _{d(off)}	R _g =	6.2 Ω, R _D see fig. 10	= 52 Ω ^b	-	120	-	- ns
Fall Time	t _f	-	see lig. It		-	39	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-		
Internal Source Inductance	L _S			-	13	-	nH	
Drain-Source Body Diode Characteristic	S	•						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	^	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21	A	
Body Diode Voltage	V _{SD}	$T_{J} = 25 \text{ °C}, I_{S} = 3.8 \text{ A}, V_{GS} = 0 \text{ V}^{b}$		-	-	1.8	V	
Body Diode Reverse Recovery Time	t _{rr}	T.=	25 °C. I⊧ =	3.8 A.	-	650	980	ns
Body Diode Reverse Recovery Charge	Q _{rr}	T _J = 25 °C, I _F = 3.8 A, dl/dt = 100 A/μs ^b		-	3.8	5.7	μC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				Ln)		

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.

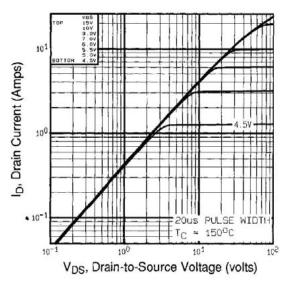
SiHFPF40-VB





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)







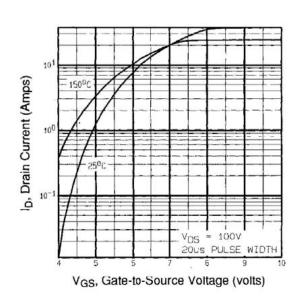
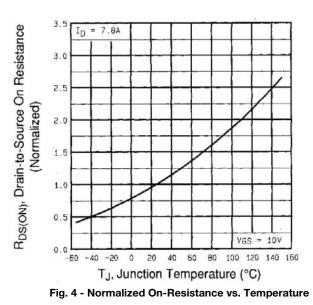


Fig. 3 - Typical Transfer Characteristics



SiHFPF40-VB



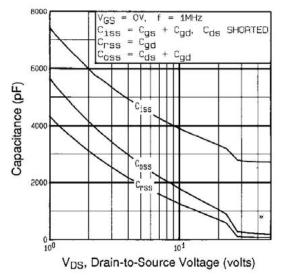
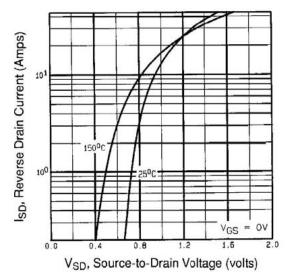


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage





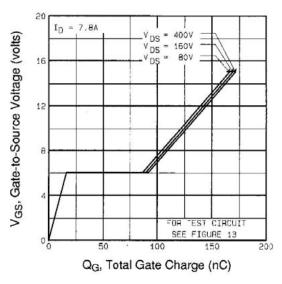
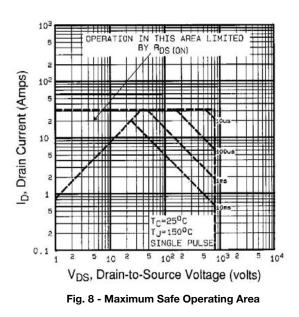


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



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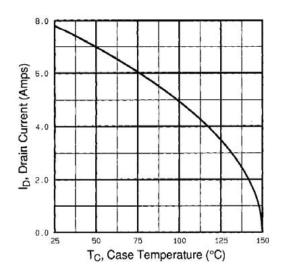


Fig. 9 - Maximum Drain Current vs. Case Temperature

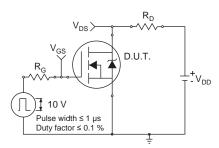


Fig. 10a - Switching Time Test Circuit

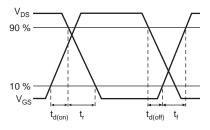


Fig. 10b - Switching Time Waveforms

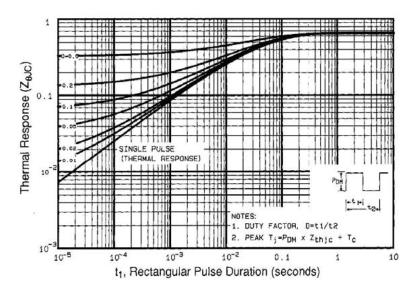


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



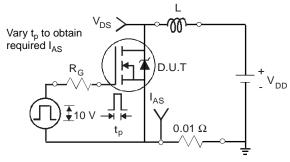


Fig. 12a - Unclamped Inductive Test Circuit

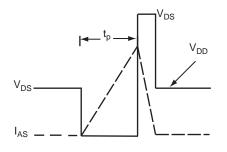


Fig. 12b - Unclamped Inductive Waveforms

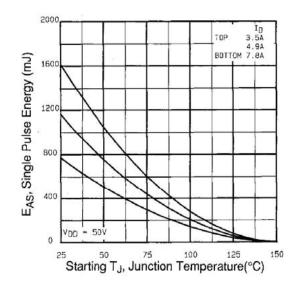


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

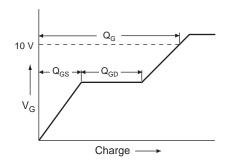
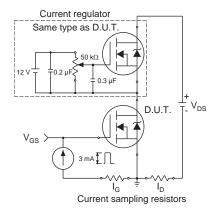


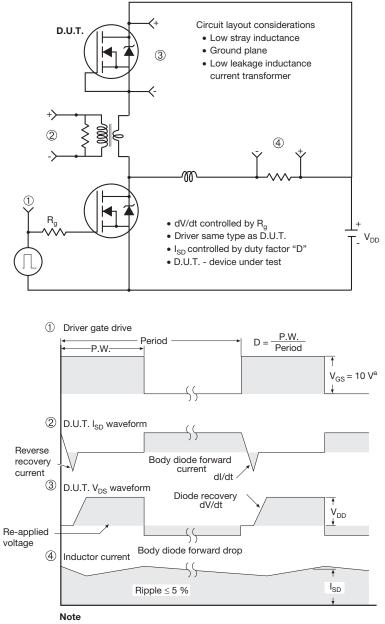
Fig. 13a - Basic Gate Charge Waveform







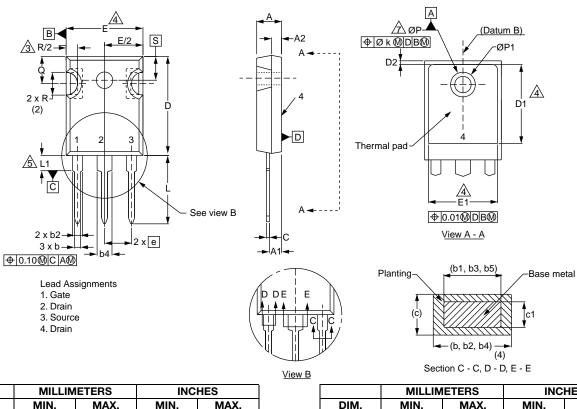
Peak Diode Recovery dV/dt Test Circuit



a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel





TO-247AC (High Voltage)

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
A	4.58	5.31	0.180	0.209
A1	2.21	2.59	0.087	0.102
A2	1.17	2.49	0.046	0.098
b	0.99	1.40	0.039	0.055
b1	0.99	1.35	0.039	0.053
b2	1.53	2.39	0.060	0.094
b3	1.65	2.37	0.065	0.093
b4	2.42	3.43	0.095	0.135
b5	2.59	3.38	0.102	0.133
С	0.38	0.86	0.015	0.034
c1	0.38	0.76	0.015	0.030
D	19.71	20.82	0.776	0.820
D1	13.08	-	0.515	-

	MILLIMETERS		INCHES	
DIM.	MIN.	MAX.	MIN.	MAX.
D2	0.51	1.30	0.020	0.051
E	15.29	15.87	0.602	0.625
E1	13.72	-	0.540	-
е	5.46 BSC		0.215 BSC	
Øk	0.254		0.010	
L	14.20	16.25	0.559	0.640
L1	3.71	4.29	0.146	0.169
N	7.62	7.62 BSC		BSC
ØР	3.51	3.66	0.138	0.144
Ø P1	-	7.39	-	0.291
Q	5.31	5.69	0.209	0.224
R	4.52	5.49	0.178	0.216
S	5.51 BSC		0.217 BSC	



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